

**Preliminary Amendment**

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Title: ELECTRICAL CIRCUIT AND METHOD FOR TESTING ELECTRONIC COMPONENT

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**IN THE ABSTRACT**

Please replace the Abstract with the following rewritten paragraph:

Abstract

**ELECTRICAL CIRCUIT AND METHOD FOR TESTING INTEGRATED CIRCUITS**

**Abstract**

An electrical test circuit is disclosed. In one embodiment, ~~The~~ electrical test circuit ~~(5) comprises~~ includes a first input ~~(51)~~ for receiving a test signal of an integrated circuit ~~(4)~~, a second input ~~(52)~~ for receiving a control signal and a third input ~~(53)~~ for receiving a normalized reference signal, particularly one that is formed to be synchronous with the test signal. Using a control device ~~(55)~~ of the electrical test circuit ~~(5)~~, the deviation and/or the amplitude and/or the phase of the reference signal and/or of the test signal can be varied. A measuring device ~~(56)~~ generates, by subtracting the reference signal from the test signal, a difference signal which is output via an output ~~(54)~~.

~~(Fig. 2)~~